

Influence of ZnO-Nb₂O₅ Substitution on Microwave Dielectric Properties of the ZrTiO₄ System

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ABSTRACT

Microwave dielectric characteristics and physical properties of the new Zr_{1-x}(Zn_{1/3}Nb_{2/3})_xTiO₄ (0.2 ≤ x ≤ 1.0) system have been investigated as a function of the amount of Zn_{1/3}Nb_{2/3}O₂ substitution. With increasing Zn_{1/3}Nb_{2/3}O₂ content (x), two phase regions were observed: α-PbO₂ solid solution (x < 0.4), mixture of the rutile type Zn_{1/3}Nb_{2/3}TiO₄ and the α-PbO₂ solid solution (x ≥ 0.4). In the α-PbO₂ solid solution region below x < 0.4, the Q·f₀ value sharply increased and the Temperature Coefficient of the Resonant Frequency (TCF) decreased with increasing Zn_{1/3}Nb_{2/3}O₂ contents while dielectric constant (K) showed nearly same value. In the mixture region above x ≥ 0.4, the dielectric constant and TCF increased with increasing Zn_{1/3}Nb_{2/3}O₂ content. Zr_{1-x}(Zn_{1/3}Nb_{2/3})_xTiO₄ materials have excellent microwave dielectric properties with K=44.0, Q·f₀=41000 GHz and TCF=-3.0 ppm/°C at x=0.35.

Key words: ZnO-Nb₂O₅, Microwave dielectric, ZrTiO₄

1. Introduction

Microwave dielectric materials have been utilized for filters and for stabilizer of the frequency of oscillation in microwave integrated circuits. The dielectric resonators or duplexer are required small size, low insertion loss and temperature stability in the microwave frequencies. Therefore, the materials for use in the microwave components are required to have a high dielectric constant (K), high Q (≡ 1/tan δ) and small Temperature Coefficient of the Resonant Frequency (TCF).

Many types of microwave dielectric materials have been investigated to meet the requirements of the microwave applications.¹⁻³⁾ Zr_xSn_yTi_zO₄ (x+y+z=2) systems are widely investigated because of their superior microwave dielectric properties, nearly zero TCF value, and high Q·f₀ value.⁴⁾ Zr_xSn_yTi_zO₄ (x+y+z=2) materials are ZrTiO₄ based solid solutions with α-PbO₂ type structure.⁵⁾ It has been found that zirconium tin titanate powders do not readily sinter by solid state diffusion, therefore sintering agents, such as ZnO, have been added to achieve good densification at temperatures between 1300~1400°C.⁶⁾ There are numerous reports on the role of sintering agent, additives such as ZnO, Nb₂O₅, La₂O₃, Ta₂O₅, Sb₂O₅, in Zr_xSn_yTi_zO₄ ceramics.⁶⁻⁸⁾ Sintering agent or additives used for zirconium tin titanate ceramics are added as a single or a combination of two or more oxides from ZnO, Nb₂O₅, La₂O₃, Ta₂O₅, and Sb₂O₅.

The substitution of Zr⁴⁺ ions of ZrTiO₄ by other ions would

affect the microwave dielectric properties and the densification of the specimens. The ionic sizes of the Zn²⁺ ion (0.74 Å, coordination number=6) and Nb⁵⁺ ion (0.64 Å, C.N.=6) were similar to that of Zr⁴⁺ ion (0.72 Å, C.N.=6).⁹⁾ Therefore, tetravalent Zr⁴⁺ ion could be substituted by one third of Zn²⁺ ion and two thirds of Nb⁵⁺ ions in the ZrTiO₄. In this study, the microwave dielectric properties of Zr_{1-x}(Zn_{1/3}Nb_{2/3})_xTiO₄ (0.2 ≤ x ≤ 1.0) system have been investigated with the substitution of ZrO₂ by Zn_{1/3}Nb_{2/3}O₂.

2. Experimental Procedures

ZrO₂ (Millennium Co., Henderson, Australia), ZnO (Hayashi Pure Chemical Co., Tokyo, Japan), Nb₂O₅ (Aldrich Chemical Co., Milwaukee, WI) and TiO₂ (Fuji-Titan, Tokyo, Japan) with >99.5% purity were used as starting materials. The powders were weighed according to the composition Zr_{1-x}(Zn_{1/3}Nb_{2/3})_xTiO₄ (0.2 ≤ x ≤ 1.0) and milled with ZrO₂ balls for 24 h in deionized water and then dried. The dried powders were calcined at 1000°C for 2 h and milled for 1h with 2.0 mm diameter zirconia balls in polyethylene jars using a planetary mill. The milled powders were dried and granulated with PVA binder and pressed into a 14 mm diameter disk. These pellets were sintered at 1250°C for 3 h. The heating rate was 5°C/min and the cooling rate was 3°C/min down to 900°C. X-Ray Powder Diffraction (XRD) analysis was used to identify the phases of the samples. The reflectivity spectra were measured using a Fourier transform infrared spectrometer (Model DA-8.12, Bomem Inc., Canada) from 50 to 4000 cm⁻¹. Dielectric constant and Q·f₀ value at microwave frequencies were measured by the post resonant method developed by Hakki and Coleman,¹⁰⁾ which consisted of parallel conducting plates and coaxial probes on

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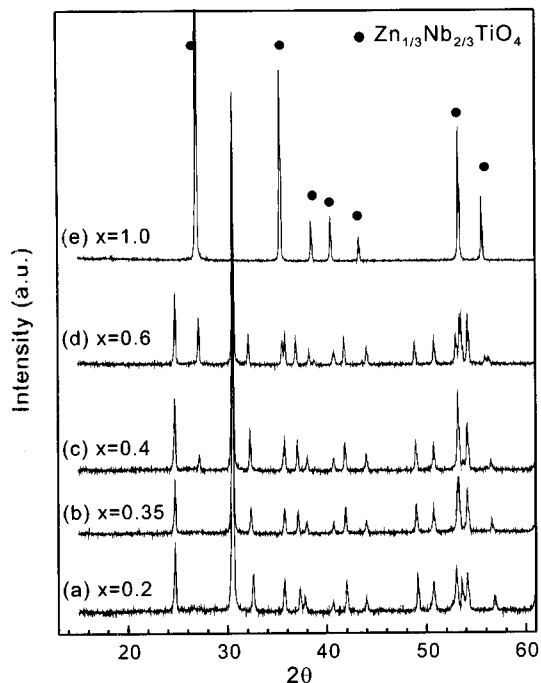


Fig. 1. X-ray diffraction patterns of $Zr_{1-x}(Zn_{1/3}Nb_{2/3})_xTiO_4$ powders sintered at 1250°C for 3 h; (a) $x=0.2$, (b) $x=0.35$, (c) $x=0.4$, (d) $x=0.6$, and (e) $x=1.0$.

the TE_{011} mode (where TE_{011} is transverse electric waves in y and z direction) at 5 GHz. And the TCF was measured using a cavity in the temperature range from 20°C to 85°C at 4 GHz.

3. Results and Discussion

Fig. 1 shows the X-ray powder diffraction patterns of the $Zr_{1-x}(Zn_{1/3}Nb_{2/3})_xTiO_4$ specimens sintered at 1250°C for 3 h with increasing $Zn_{1/3}Nb_{2/3}O_2$ contents. Orthorhombic α -PbO₂ type solid solutions⁵⁾ were obtained from $x=0.2$ to $x=0.35$ and there was no secondary phase. With further substitution of $Zn_{1/3}Nb_{2/3}O_2$ above $x=0.4$, rutile type $Zn_{1/3}Nb_{2/3}TiO_4$ phase was detected. The solid solution range of the $Zr_{1-x}(Zn_{1/3}Nb_{2/3})_xTiO_4$ system was similar to that of the $Zr_{1-x}Sn_xTiO_4$ systems.⁵⁾ And the amount of the secondary phase $Zn_{1/3}Nb_{2/3}TiO_4$ was increased with increasing $Zn_{1/3}Nb_{2/3}O_2$ contents. At $x=1.0$ only $Zn_{1/3}Nb_{2/3}TiO_4$ phase was observed. From the XRD results as shown on Fig. 1, two regions were observed in the $Zr_{1-x}(Zn_{1/3}Nb_{2/3})_xTiO_4$ system with increasing amount of $Zn_{1/3}Nb_{2/3}O_2$: α -PbO₂ type solid solutions below $x=0.4$, mixture of the rutile type $Zn_{1/3}Nb_{2/3}TiO_4$ and the α -PbO₂ type solid solutions, above $x=0.4$. The relative density of $Zr_{1-x}(Zn_{1/3}Nb_{2/3})_xTiO_4$ specimens was over 96% in the whole composition range. For the specimen sintered at 1250°C for 3 h, the relative density of $ZrTiO_4$ was about 70% of theoretical density. Therefore, the sinterability of the specimens was enhanced by the substitution of $Zn_{1/3}Nb_{2/3}O_2$ to ZrO_2 in the $ZrTiO_4$.

In order to obtain the calculated dielectric constant and intrinsic loss, far infrared reflectivity spectrum was mea-

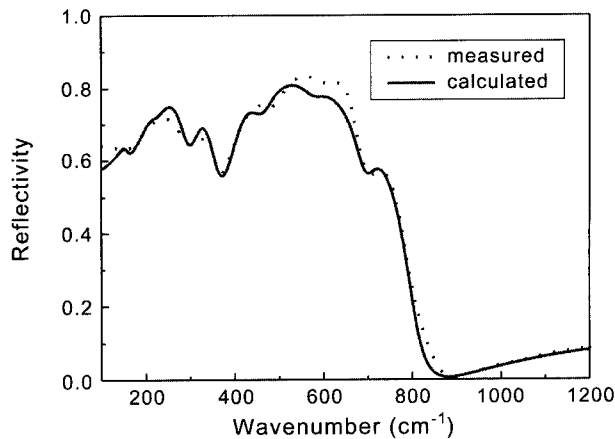


Fig. 2. Infrared reflectivity spectrum of the $Zr_{1-x}(Zn_{1/3}Nb_{2/3})_xTiO_4$ ($x=0.35$) specimen.

Table 1. Dispersion Parameters of $Zr_{1-x}(Zn_{1/3}Nb_{2/3})_xTiO_4$ Specimen ($x=0.35$) Obtained from the Best Fit to the Reflectivity Data

j	$Zr_{1-x}(Zn_{1/3}Nb_{2/3})_xTiO_4$ ($x=0.35$)				$ZrTiO_4$ ¹²⁾		
	ω_j (cm ⁻¹)	γ_j (cm ⁻¹)	$\Delta\epsilon_j$	$\tan \delta_j$ ($\times 10^{-5}$)	ω_j (cm ⁻¹)	γ_j (cm ⁻¹)	$\Delta\epsilon_j$
1	155	28	3.5	2.1778	145	043.5	5.0
2	210	42	11.0	5.5859			
3	245	53	15.1	7.0885	240	72	11.5
4	316	50	3.5	9.3361	318	47.7	2.6
5	406	65	4.4	9.2571	422	92.8	13.6
6	470	70	1.0	1.6936	500	30	1.6
7	580	65	0.06	5.7731			
8	699	60	0.05	3.3722	705	28.2	0.03
$\epsilon_\infty=5.2$					$\epsilon_\infty=8.0$		

sured. Fig. 2 shows the measured and calculated reflectivity spectra of the $Zr_{1-x}(Zn_{1/3}Nb_{2/3})_xTiO_4$ ($x=0.35$) solid solution system. The measured spectrum was very similar to the $ZrTiO_4$ specimen.¹²⁾ The calculated reflectivity spectrum was well fitted with the measured one. Table 1 shows the dispersion parameters of $Zr_{1-x}(Zn_{1/3}Nb_{2/3})_xTiO_4$ specimen ($x=0.35$) obtained from the best fit to the reflectivity data. ω_j , γ_j , and $\Delta\epsilon_j$ is the resonant frequency, damping constant and modes contribution to the dielectric constant of the j th mode, respectively, and ϵ_∞ is the dielectric constant caused by the electronic polarization at higher frequencies.^{2,3)} The calculated dielectric constant and $Q \cdot f_0$ value were 43.8 and 41444 GHz from Table 1.

Fig. 3 shows the dielectric constant of the $Zr_{1-x}(Zn_{1/3}Nb_{2/3})_xTiO_4$ specimens with increasing $Zn_{1/3}Nb_{2/3}O_2$ contents. In the solid solution region, dielectric constant slightly increased with increasing $Zn_{1/3}Nb_{2/3}O_2$ contents. In the microwave frequency region, dielectric constant is sum of ionic and electronic polarization.¹⁰⁾ Therefore, the change of the dielectric constant in the solid solution region might be due to the change of the sum of the ionic and electronic polarization. In the mixed phase region above $x=0.4$, dielectric constant

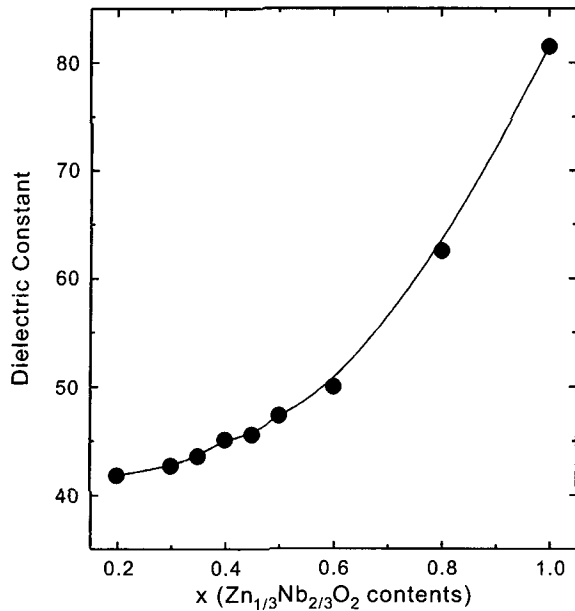


Fig. 3. Dielectric constant of $Zr_{1-x}(Zn_{1/3}Nb_{2/3})_xTiO_4$ specimens with variation of x sintered at $1250^\circ C$ for 3 h.

sharply increased with increasing $Zn_{1/3}Nb_{2/3}O_2$ contents. The dependence of the dielectric constant on the relative amount of the phases present in the sintered specimens can be explained by the logarithmic mixing rule,¹¹⁾

$$\ln k = \sum v_i \ln k_i' \quad (1)$$

where, k_i' is the dielectric constant of the i phase and v_i is the volume fraction of the i phase. The increase in the dielectric constant is due to the increase of $Zn_{1/3}Nb_{2/3}TiO_4$ phase with higher dielectric constant ($K=83$) than that of $Zr_{1-x}(Zn_{1/3}Nb_{2/3})_xTiO_4$ solid solutions.

Fig. 4 shows the $Q \cdot f_0$ values of the $Zr_{1-x}(Zn_{1/3}Nb_{2/3})_xTiO_4$ specimens with increasing $Zn_{1/3}Nb_{2/3}O_2$ contents. The $Q \cdot f_0$

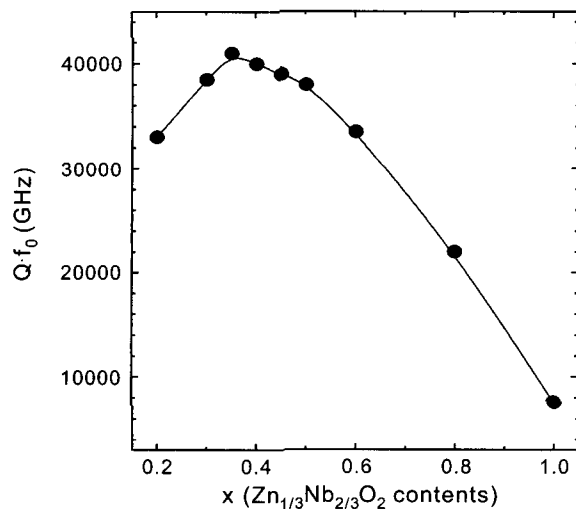


Fig. 4. $Q \cdot f_0$ of $Zr_{1-x}(Zn_{1/3}Nb_{2/3})_xTiO_4$ specimens with variation of x sintered at $1250^\circ C$ for 3 h.

value increased with increasing up to $x=0.35$, reaching as high as 41,000 GHz. The $Q \cdot f_0$ values of the $Zr_{1-x}(Zn_{1/3}Nb_{2/3})_xTiO_4$ specimens in the solid solution range were much higher values than that of the $ZrTiO_4$ specimen ($Q \cdot f_0=21,000\sim 30,000$ GHz).¹²⁾ The $Q \cdot f_0$ value depends on the extrinsic factors such as microstructure, secondary phases and sintering density and intrinsic ones representing the minimum loss related with lattice anharmonicity that can be expected for a particular materials composition and crystal structure.^{7,13)} The effects of density and secondary phase on the $Q \cdot f_0$ value of the $Zr_{1-x}(Zn_{1/3}Nb_{2/3})_xTiO_4$ specimens could be neglected because the relative density was higher than 96%⁷⁾ and there was no secondary phase in the solid solution range as shown in Fig. 1. Therefore, the increase of the $Q \cdot f_0$ value of $Zr_{1-x}(Zn_{1/3}Nb_{2/3})_xTiO_4$ specimens was related to the decrease of the anharmonicity of the ions in the solid solution limit as confirmed by Table 1. In the mixed phase region, further substitution of $Zn_{1/3}Nb_{2/3}O_2$ over $x=0.4$ caused the decrease of the $Q \cdot f_0$ value due to the formation of a secondary phase. $Zn_{1/3}Nb_{2/3}TiO_4$ secondary phase has a lower $Q \cdot f_0$ value ($Q \cdot f_0=7500$ GHz) value than that of $Zr_{1-x}(Zn_{1/3}Nb_{2/3})_xTiO_4$ solid solutions.

Fig. 5 shows the Temperature Coefficient of the Resonant Frequency (TCF) as a function of the amount of $Zn_{1/3}Nb_{2/3}O_2$. It is reported that the Temperature Coefficient of the Resonant Frequency (TCF) value of $ZrTiO_4$ phase is about 59 ppm/ $^\circ C$.¹²⁾ In the $Zr_{1-x}(Zn_{1/3}Nb_{2/3})_xTiO_4$ systems, the substitution of ZrO_2 by $Zn_{1/3}Nb_{2/3}O_2$ led to decrease TCF value up to $x=0.35$. At $x=0.3$, nearly zero TCF value was obtained. In the mixed phase region, mixture of the α - PbO_2 type solid solutions and rutile type $Zn_{1/3}Nb_{2/3}TiO_4$ phase, TCF value increased with increasing $Zn_{1/3}Nb_{2/3}O_2$ contents. The dependence of the TCF in the mixed phase region with increasing

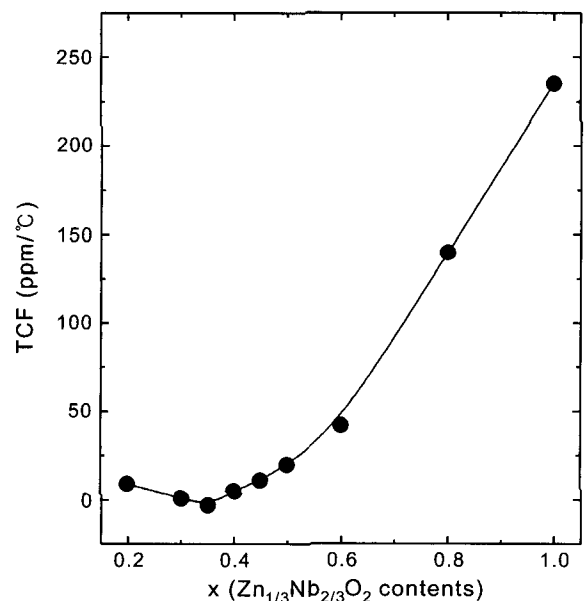


Fig. 5. TCF of $Zr_{1-x}(Zn_{1/3}Nb_{2/3})_xTiO_4$ specimens with variation of x sintered at $1250^\circ C$ for 3 h.

Zn_{1/3}Nb_{2/3}O₂ contents could be explained by the volume mixing rule¹¹ of the constituent phases. Excellent microwave dielectric properties was obtained at around x=0.35 in the Zr_{1-x}(Zn_{1/3}Nb_{2/3})_xTiO₄ system: K of 44, Q·f₀ of 41,000 GHz, and TCF of -3.0 ppm/°C at x=0.35.

4. Conclusions

In the new Zr_{1-x}(Zn_{1/3}Nb_{2/3})_xTiO₄ (0.2≤x≤1.0) system, microwave dielectric properties could be controlled by the substitution of ZrO₂ by Zn_{1/3}Nb_{2/3}O₂. With increasing Zn_{1/3}Nb_{2/3}O₂ content (x), the α-PbO₂ solid solution were observed for the specimens below x=0.4, while the mixture of the rutile type Zn_{1/3}Nb_{2/3}TiO₄ and the α-PbO₂ solid solutions were observed above x=0.4. In the α-PbO₂ solid solution region, the Q·f₀ value sharply increased and the Temperature Coefficient of the Resonant Frequency (TCF) decreased with increasing Zn_{1/3}Nb_{2/3}O₂ contents. The specimens with x=0.35 showed excellent microwave dielectric properties: a dielectric constant of 44, Q·f₀=41,000 GHz, and TCF=-3.0 ppm/°C. In the mixture phase region, the variation of the dielectric constant and TCF was explained by mixing rule of the present phases between Zr_{1-x}(Zn_{1/3}Nb_{2/3})_xTiO₄ solid solution and Zn_{1/3}Nb_{2/3}TiO₄ phase.

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